


**OptiMOS<sup>(TM)</sup>3 Power-Transistor**
**Features**

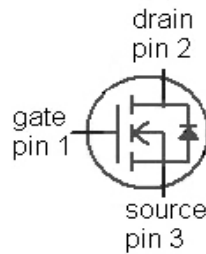
- Ideal for high frequency switching and sync. rec.
- Optimized technology for DC/DC converters
- Excellent gate charge x  $R_{DS(on)}$  product (FOM)
- Very low on-resistance  $R_{DS(on)}$
- N-channel, normal level
- 100% avalanche tested
- Pb-free plating; RoHS compliant
- Qualified according to JEDEC<sup>1)</sup> for target applications

**Product Summary**

$V_{DS}$	60	V
$R_{DS(on),max}$	3.4	m $\Omega$
$I_D$	100	A



<b>Type</b>	IPD034N06N3 G
	
<b>Package</b>	PG-TO252-3
<b>Marking</b>	034N06N


**Maximum ratings, at  $T_j=25\text{ }^\circ\text{C}$ , unless otherwise specified**

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	$I_D$	$T_C=25\text{ }^\circ\text{C}^2)$	100	A
		$T_C=100\text{ }^\circ\text{C}$	100	
Pulsed drain current <sup>3)</sup>	$I_{D,pulse}$	$T_C=25\text{ }^\circ\text{C}$	400	
Avalanche energy, single pulse	$E_{AS}$	$I_D=100\text{ A}$ , $R_{GS}=25\text{ }\Omega$	149	mJ
Gate source voltage	$V_{GS}$		$\pm 20$	V
Power dissipation	$P_{tot}$	$T_C=25\text{ }^\circ\text{C}$	167	W
Operating and storage temperature	$T_j$ , $T_{stg}$		-55 ... 175	$^\circ\text{C}$
IEC climatic category; DIN IEC 68-1			55/175/56	

<sup>1)</sup>J-STD20 and JESD22

<sup>2)</sup> Current is limited by bondwire; with an  $R_{thjC}=0.9\text{ K/W}$  the chip is able to carry 164 A.

<sup>3)</sup> See figure 3 for more detailed information

<sup>4)</sup> See figure 13 for more detailed information

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

**Thermal characteristics**

Thermal resistance, junction - case	$R_{thJC}$		-	-	0.9	K/W
Thermal resistance, junction - ambient	$R_{thJA}$	minimal footprint	-	-	62	
		6 cm <sup>2</sup> cooling area <sup>5)</sup>	-	-	40	

**Electrical characteristics, at  $T_j=25\text{ °C}$ , unless otherwise specified**
**Static characteristics**

Drain-source breakdown voltage	$V_{(BR)DSS}$	$V_{GS}=0\text{ V}, I_D=1\text{ mA}$	60	-	-	V
Gate threshold voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=93\text{ }\mu\text{A}$	2	3	4	
Zero gate voltage drain current	$I_{DSS}$	$V_{DS}=60\text{ V}, V_{GS}=0\text{ V}, T_j=25\text{ °C}$	-	0.1	1	$\mu\text{A}$
		$V_{DS}=60\text{ V}, V_{GS}=0\text{ V}, T_j=125\text{ °C}$	-	10	100	
Gate-source leakage current	$I_{GSS}$	$V_{GS}=20\text{ V}, V_{DS}=0\text{ V}$	-	1	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	$V_{GS}=10\text{ V}, I_D=100\text{ A}$	-	2.8	3.4	m $\Omega$
Gate resistance	$R_G$		-	1.3	-	$\Omega$
Transconductance	$g_{fs}$	$ V_{DS} >2 I_D R_{DS(on)max}, I_D=100\text{ A}$	75	149	-	S

<sup>5)</sup> Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm<sup>2</sup> (one layer, 70  $\mu\text{m}$  thick) copper area for drain connection. PCB is vertical in still air.

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

**Dynamic characteristics**

Input capacitance	$C_{iss}$	$V_{GS}=0\text{ V}, V_{DS}=30\text{ V},$ $f=1\text{ MHz}$	-	8000	11000	pF
Output capacitance	$C_{oss}$		-	1700	2300	
Reverse transfer capacitance	$C_{rss}$		-	58	-	
Turn-on delay time	$t_{d(on)}$	$V_{DD}=30\text{ V}, V_{GS}=10\text{ V},$ $I_D=90\text{ A}, R_G=3.2\ \Omega$	-	38	-	ns
Rise time	$t_r$		-	161	-	
Turn-off delay time	$t_{d(off)}$		-	63	-	
Fall time	$t_f$		-	16	-	

**Gate Charge Characteristics<sup>6)</sup>**

Gate to source charge	$Q_{gs}$	$V_{DD}=30\text{ V}, I_D=100\text{ A},$ $V_{GS}=0\text{ to }10\text{ V}$	-	43	-	nC
Gate to drain charge	$Q_{gd}$		-	9	-	
Switching charge	$Q_{sw}$		-	28	-	
Gate charge total	$Q_g$		-	98	130	
Gate plateau voltage	$V_{plateau}$		-	5.4	-	V
Output charge	$Q_{oss}$	$V_{DD}=30\text{ V}, V_{GS}=0\text{ V}$	-	79	105	nC

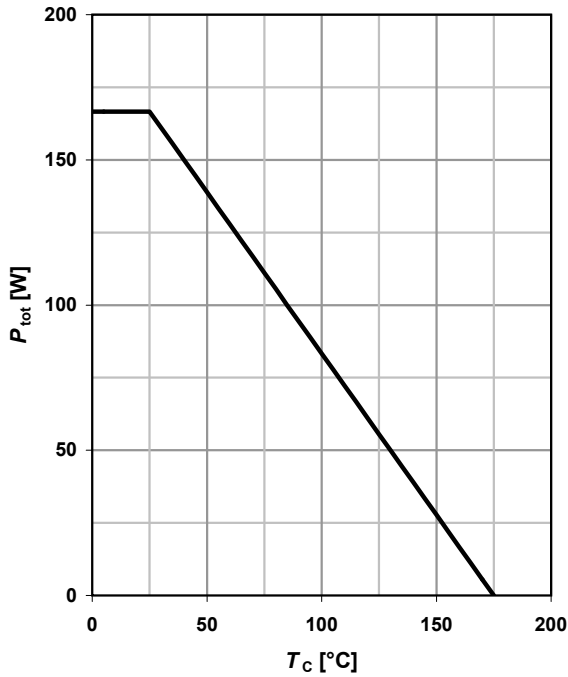
**Reverse Diode**

Diode continuous forward current	$I_S$	$T_C=25\text{ }^\circ\text{C}$	-	-	100	A
Diode pulse current	$I_{S,pulse}$		-	-	400	
Diode forward voltage	$V_{SD}$	$V_{GS}=0\text{ V}, I_F=100\text{ A},$ $T_j=25\text{ }^\circ\text{C}$	-	0.9	1.2	V
Reverse recovery time	$t_{rr}$	$V_R=30\text{ V}, I_F=90\text{ A},$ $di_F/dt=100\text{ A}/\mu\text{s}$	-	48	-	ns
Reverse recovery charge	$Q_{rr}$		-	73	-	nC

<sup>6)</sup> See figure 16 for gate charge parameter definition

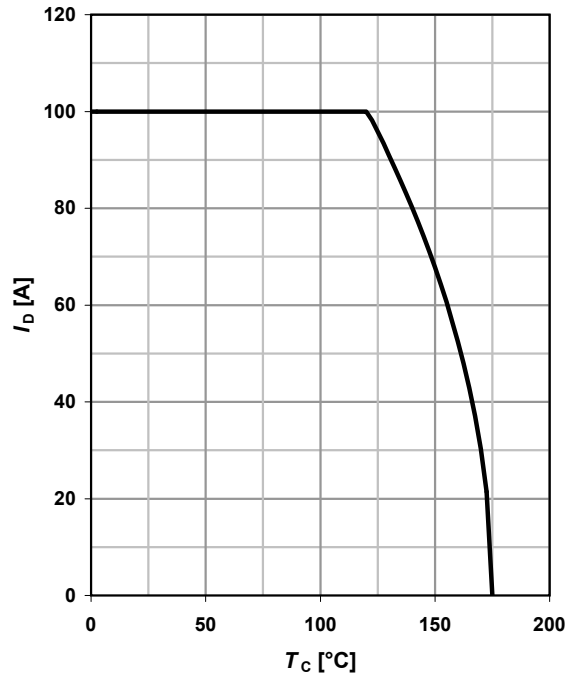
**1 Power dissipation**

$$P_{tot} = f(T_C)$$



**2 Drain current**

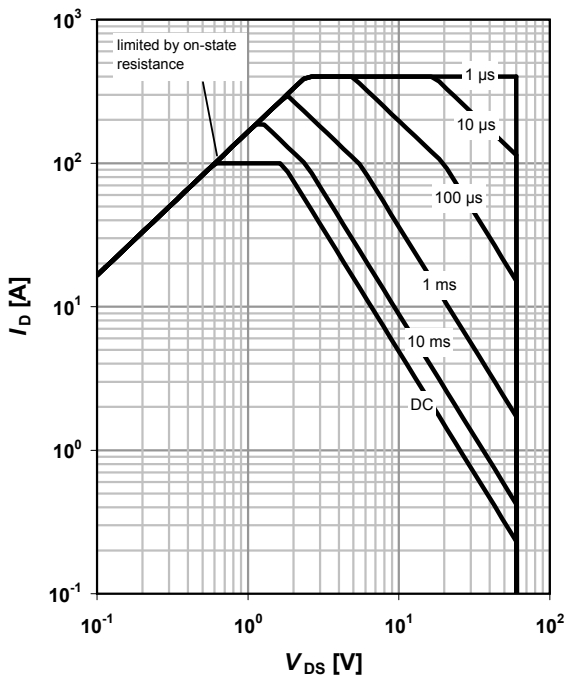
$$I_D = f(T_C); V_{GS} \geq 10 \text{ V}$$



**3 Safe operating area**

$$I_D = f(V_{DS}); T_C = 25 \text{ °C}; D = 0$$

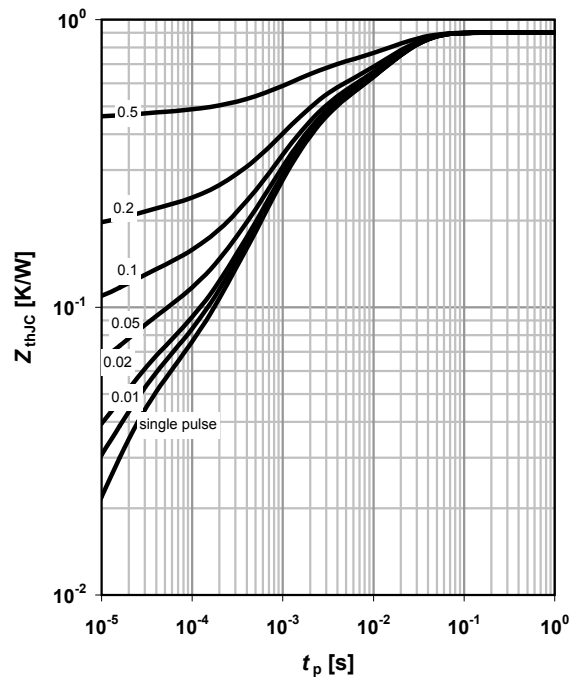
parameter:  $t_p$



**4 Max. transient thermal impedance**

$$Z_{thJC} = f(t_p)$$

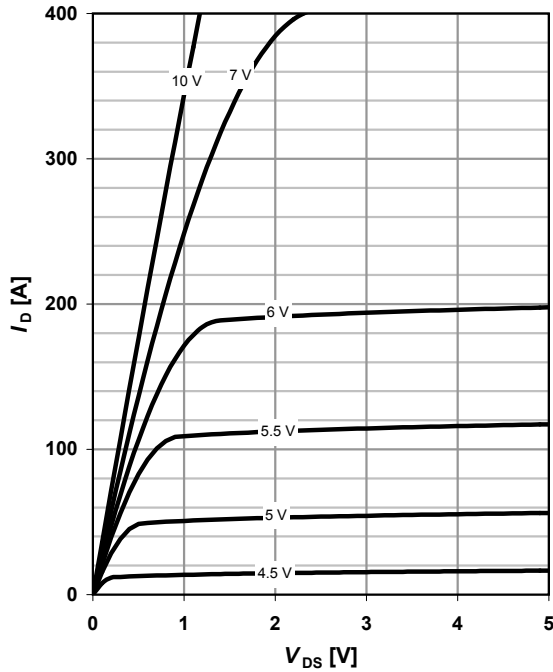
parameter:  $D = t_p / T$



**5 Typ. output characteristics**

$I_D = f(V_{DS}); T_j = 25\text{ }^\circ\text{C}$

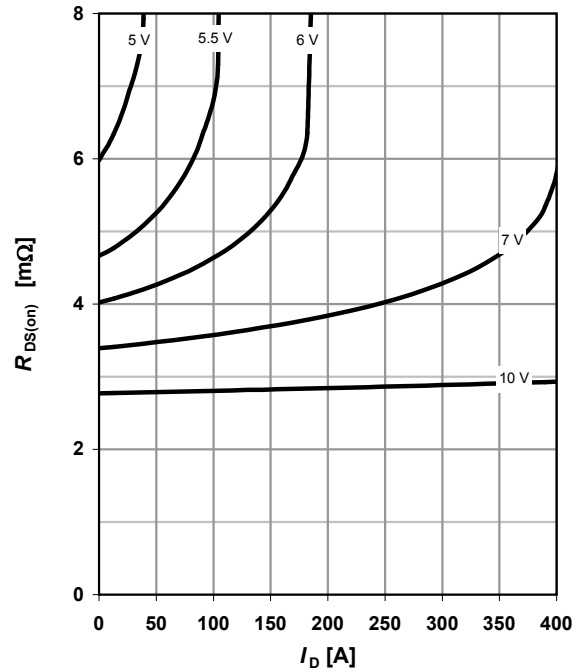
parameter:  $V_{GS}$



**6 Typ. drain-source on resistance**

$R_{DS(on)} = f(I_D); T_j = 25\text{ }^\circ\text{C}$

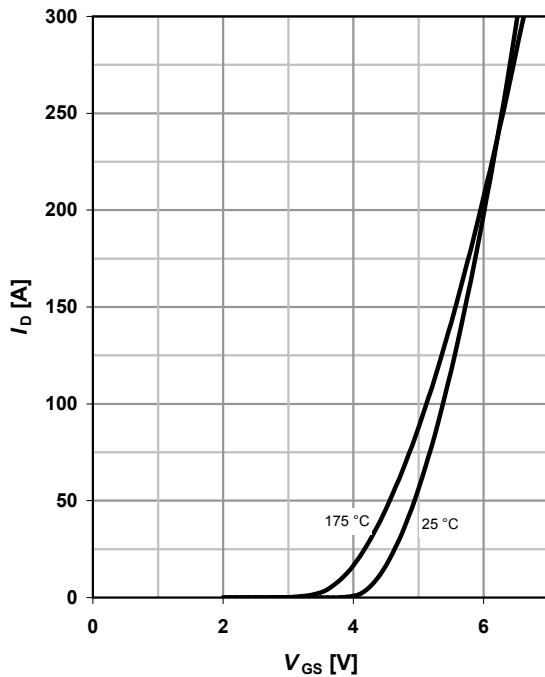
parameter:  $V_{GS}$



**7 Typ. transfer characteristics**

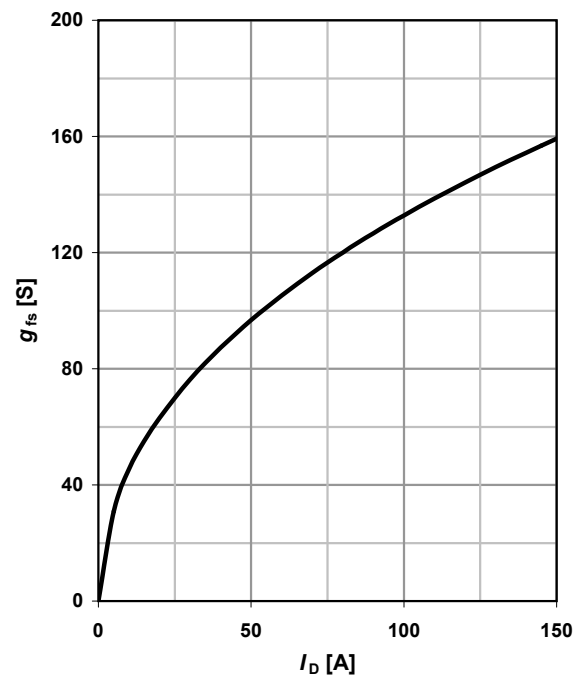
$I_D = f(V_{GS}); |V_{DS}| > 2|I_D|R_{DS(on)max}$

parameter:  $T_j$



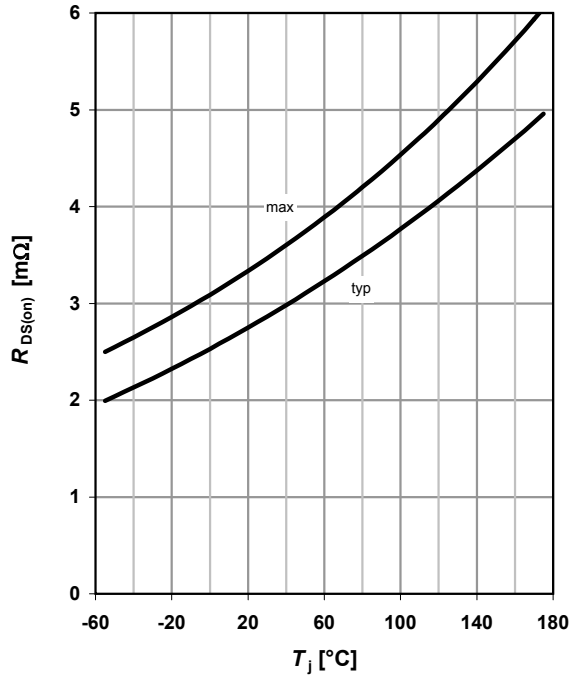
**8 Typ. forward transconductance**

$g_{fs} = f(I_D); T_j = 25\text{ }^\circ\text{C}$

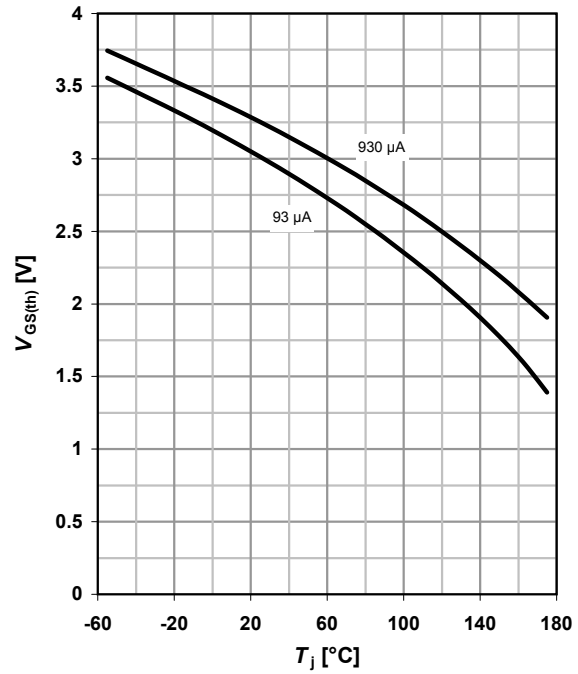


**9 Drain-source on-state resistance**

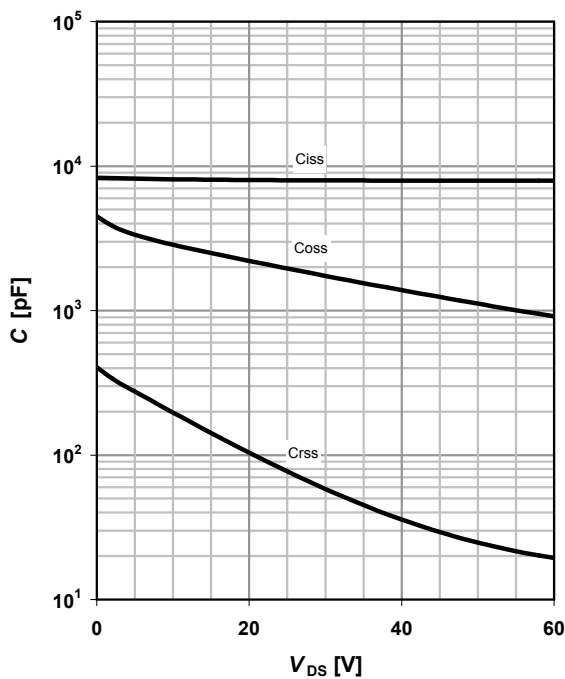
$$R_{DS(on)} = f(T_j); I_D = 100 \text{ A}; V_{GS} = 10 \text{ V}$$


**10 Typ. gate threshold voltage**

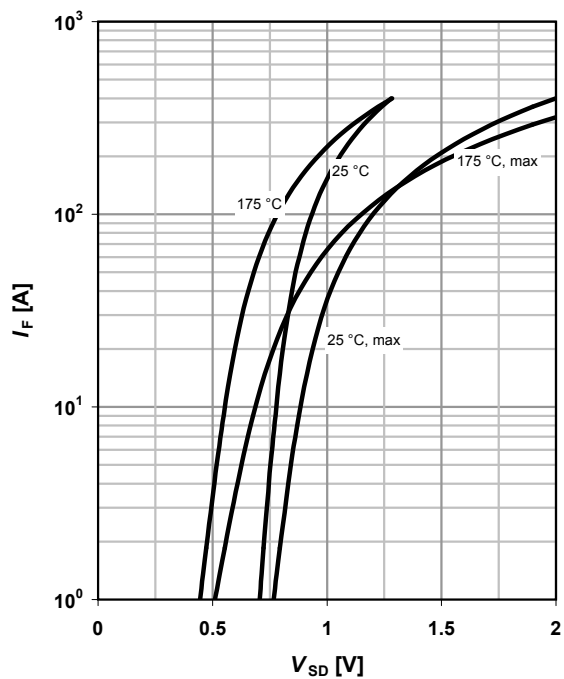
$$V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$$

 parameter:  $I_D$ 

**11 Typ. capacitances**

$$C = f(V_{DS}); V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$$


**12 Forward characteristics of reverse diode**

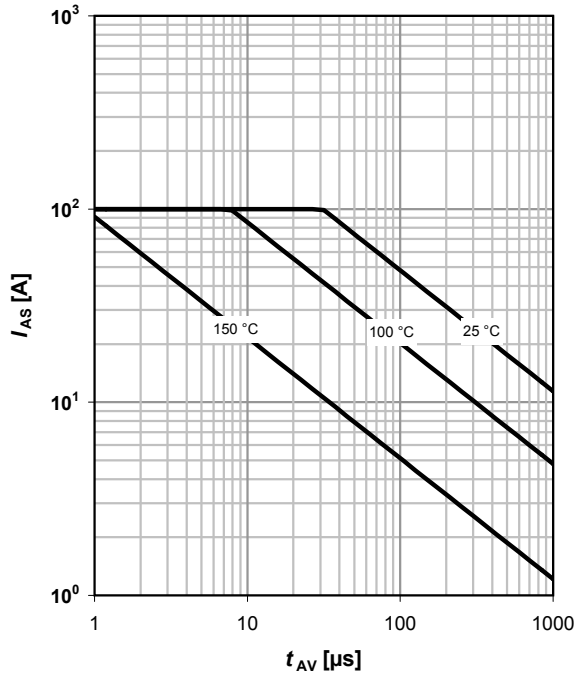
$$I_F = f(V_{SD})$$

 parameter:  $T_j$ 


**13 Avalanche characteristics**

$I_{AS}=f(t_{AV}); R_{GS}=25 \Omega$

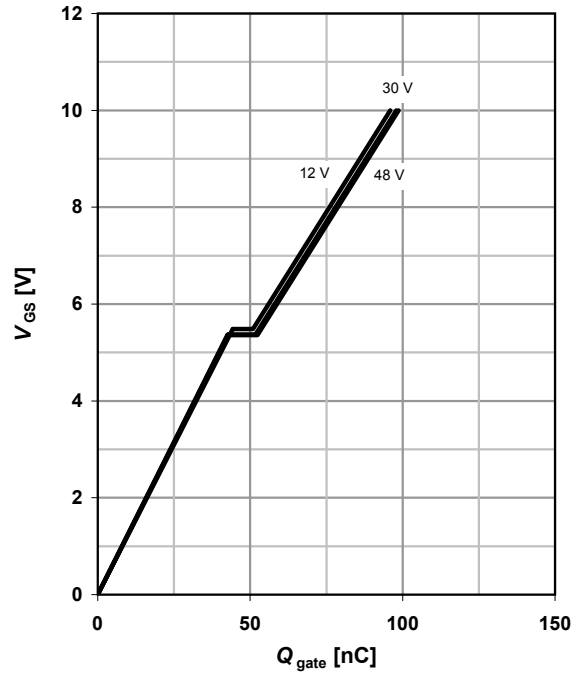
parameter:  $T_{j(start)}$



**14 Typ. gate charge**

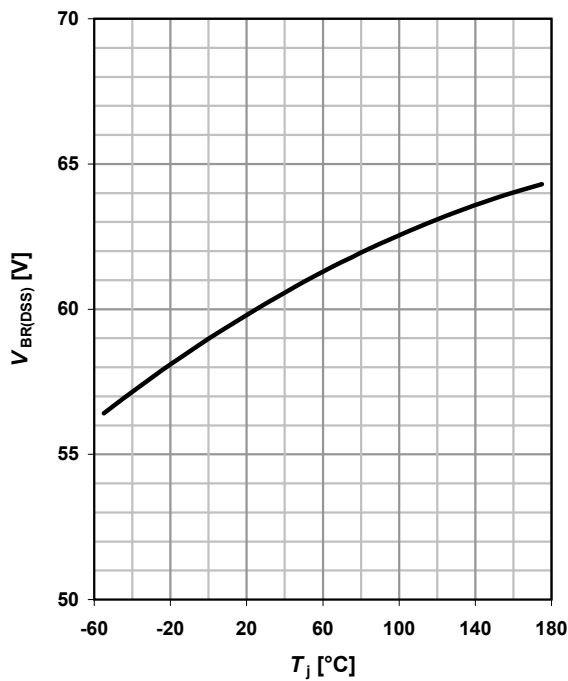
$V_{GS}=f(Q_{gate}); I_D=100 \text{ A pulsed}$

parameter:  $V_{DD}$



**15 Drain-source breakdown voltage**

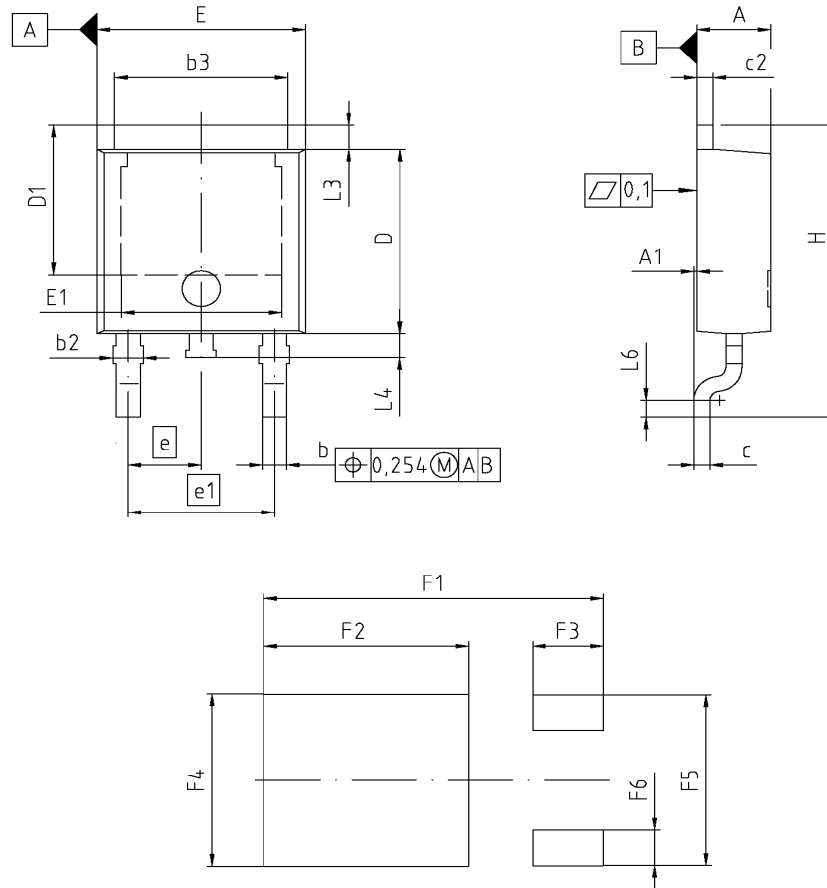
$V_{BR(DSS)}=f(T_j); I_D=1 \text{ mA}$



**16 Gate charge waveforms**



## PG-TO252-3



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
<b>A</b>	2.159	2.413	0.085	0.095
<b>A1</b>	0.000	0.150	0.000	0.006
<b>b</b>	0.635	0.889	0.025	0.035
<b>b2</b>	0.650	1.150	0.026	0.045
<b>b3</b>	5.004	5.500	0.197	0.217
<b>c</b>	0.457	0.580	0.018	0.023
<b>c2</b>	0.460	0.980	0.018	0.039
<b>D</b>	5.969	6.223	0.235	0.245
<b>D1</b>	5.020	5.842	0.198	0.230
<b>E</b>	6.400	6.731	0.252	0.265
<b>E1</b>	4.850	5.207	0.191	0.205
<b>e</b>	2.286		0.090	
<b>e1</b>	4.572		0.180	
<b>N</b>	3		3	
<b>H</b>	9.400	10.480	0.370	0.413
<b>L3</b>	0.900	1.143	0.035	0.045
<b>L4</b>	0.584	0.950	0.023	0.037
<b>L6</b>	0.510	0.686	0.020	0.027
<b>F1</b>	10.500	10.700	0.413	0.421
<b>F2</b>	6.300	6.500	0.248	0.256
<b>F3</b>	2.100	2.300	0.083	0.091
<b>F4</b>	5.700	5.900	0.224	0.232
<b>F5</b>	5.660	5.860	0.222	0.231
<b>F6</b>	1.100	1.300	0.043	0.051

**REFERENCE**  
JEDEC TO252

**SCALE**

**EUROPEAN PROJECTION**

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